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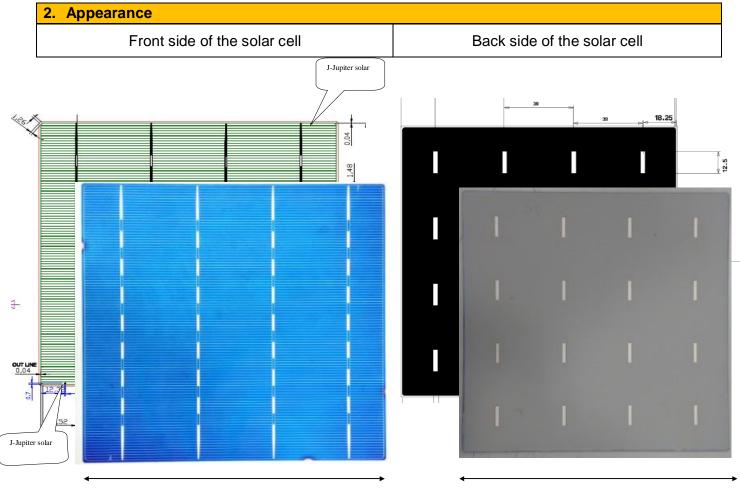
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1. Mechanical Data and Design				
Product	Multi-Crystalline Solar Cell based on virgin Poly-Silicon			
Code	JSPL-MC-4BB-FBB1.15-RBB2.4L			
Format	156 mm x 156 mm <u>+</u> 0.5 mm			
Thickness	180-235 μm			
Front side (-)	Iso – textured, blue antireflective coating (silicon nitride), 4 Bus bars padded,1.15 <u>+</u> 0.1 mm wide, 154 <u>+</u> 0.2mm length, Silver)			
Back side (+)	Soldering pads, 2.4 + 0.2 mm wide, silver, Aluminium coated (back surface field)			
Busbar distance	39 <u>+</u> 0.2 mm			



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 156 ± 0.5

154.5

3. Electrical Pe	erformance					
Efficiency Class	MC-17.00	MC-17.10	MC-17.20	MC-17.30	MC-17.40	MC-17.50
Pmpp(Wp)	4.14	4.16	4.19	4.21	4.23	4.26
Impp(A)	8.00	8.02	8.05	8.07	8.08	8.11
Vmpp(mV)	518	519	521	522	524	526
Efficiency Class	MC-17.60	MC-17.70	MC-17.80	MC-17.90	MC-18.00	MC-18.10
Pmpp(Wp)	4.28	4.31	4.33	4.36	4.38	4.40
Impp(A)	8.13	8.15	8.17	8.20	8.23	8.25
Vmpp(mV)	527	529	530	532	533	534
		·	-		·	
Efficiency Class	MC-18.20	MC-18.30	MC-18.40	MC-18.50	MC-18.60	MC-18.70
Pmpp(Wp)	4.43	4.45	4.48	4.50	4.53	4.55
Impp(A)	8.29	8.31	8.35	8.37	8.41	8.42
Vmpp(mV)	535	536	537	538	539	541

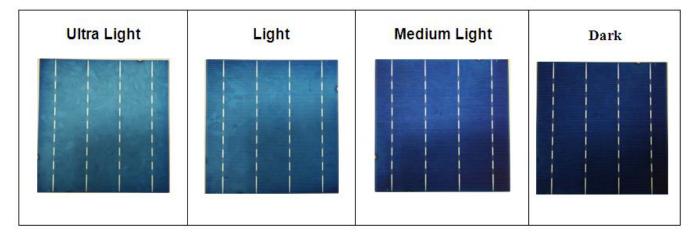


All data measured at standard testing conditions: 1000W/m², 25°C, AM1.5G IEC 60904-3 Ed.2(2008),P_{MPP} +/-1.5 % rel. Reference cell calibrated by the Fraunhofer ISE in Freiburg

4. Cells grading & Classification

Cells classified based on

- Efficiency minimum bin classification of 0.1% interval. For example JSPL-MC-18.00AL Class means, cell efficiency from 18.00 to 18.10%
- > Shunt resistance & Leakage current at -12V criteria
- > Optical appearance- i.e. Ultra Light , Light , Medium light & Dark, as below-

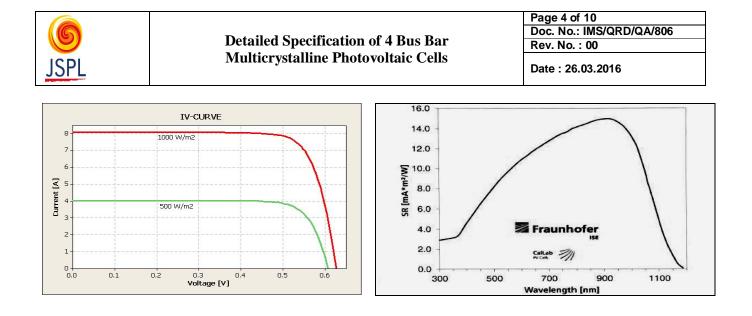


5. Behavior of electrical parameters

Temperature Coefficients		Intensity Dependence		
Power	- 0.39 %/ °C	Intensity [W/m ²]	U _{MPP} *	I _{MPP} *
Current	+0.06 %/ °C	1000	1.00	1.0
Voltage	- 0.32 %/ °C	500	0.00	0 F
-		500	0.98	0.5

*Ratio of U_{MPP} / I_{MPP} at reduced intensity to value at 1000 W/m²

6.Typical Current/Voltage-Curve and Spectral Response



7. Processing Recommendations

Solder Joint

Copper ribbons coated with 16-22 µm: 62 % Sn / 36 % Pb / 2 % Ag of Thickness 250um.

8. Reliability Test

Soldering Test	Average \geq 2.0 N & Minimum \geq 1.0 N for FBB & RBB at $180\pm3^{\circ}$ Deg pull angle
Hot water Dip test (Back AI)	If reaction taken place within 10 - 15 min at 75 \pm 5°C then failed otherwise Passed.
Tape Test(Back AI)	If Aluminium paste detached & stuck on adhesive tape then failed otherwise passed.

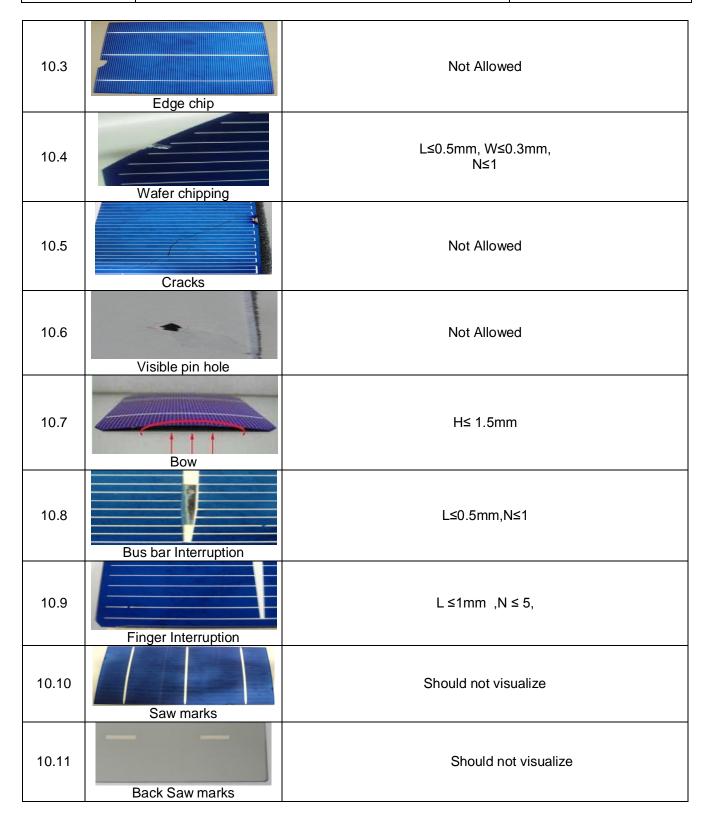
9. PID Test

As per IEC 62804 - System voltage durability qualification test for crystalline silicon Modules- PID test at 60 °C,85%RH, 96Hrs at 1000V.

10.Visual Inspection Standard(IS 2500, Inspection Level-S3, AQL2.5)

Sr.No	Defect type	A-Grade
10.1	V-Chip	Not Allowed
10.2	Corner chip	Not Allowed







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10.12	Paste marks	Area=0.2 mm2, N ≤ 2 Should be ≤ 2.5% in each packet
10.13	Finger knot	L ≤0.3 mm, W ≤0.3 mm N ≤ 2 Should be ≤ 2.5% in each packet
10.14	Strains	Area ≤1 mm2, N ≤ 2
10.15	Finger Marks	Not allowed
10.16	Front Scratch	Visual not allowed
10.17	Micro bubble	Should not burst
10.18	Back Al Missing	Area ≤ 1mm², N≤1
9.19	Back Busbar defects	L≤ 2.0mm, W≤ 1.5mm, N≤1
10.20	PECVd Marks	Not Allowed



10.21	Busbar Oxidization	Not Allowed
10.22	Back Al Scratch	Area ≤ 1mm², N≤1
10.23	Belt Mark	Should not be visualize over the entire BSF
10.24	Colour Variation*	Not Allowed (A-grade colors samples shown below)
10.25	Printing shift-Front	Printing Offset should not be more than ± 0.3 mm
10.26	Busbar misalignment– BackBus bar	Bus bar misalignment should not be more than ± 0.3 mm
10.27	Rotated finger layout (Disorientation relative to reference edge or wafer corner)	Should not be visualize with naked eye



11.Product Identification & Traceability

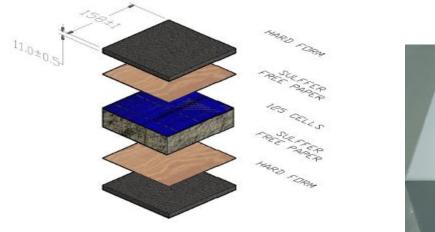
- Every primary packing having unique lot number, Eff. class, Product description, quantity and date of manufacturing
- Lot number provide the traceability of single cells with complete <u>IV data</u> Described as below

 Lot number
 Product description

JEPL	JUPITER SOLAR POWER Ltd
Cell Type	JSPL MC - 4BB - FBB1.15-RBB 2.4L,105F
LOT NO.	500499
Eff,Class,Color	JSPL - MC -18.30AL
Quantity	125
Date	2016-3-5
Sign-	Conculted
Date of Mfg	Quantity Eff. class

12. Packing

12.1 Primary Packing



a. Comprehensive view



b. Front View

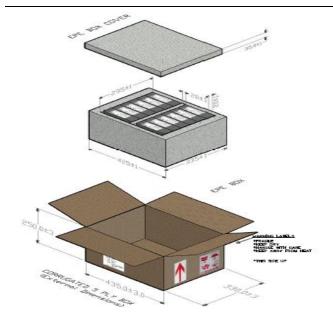
12.2 Secondary Packing



Detailed Specification of 4 Bus Bar Multicrystalline Photovoltaic Cells

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a. Comprehensive view

b. Front View





12.3 Transport Packing



13. Storage Recommendation

Solar cells are fragile and sensitive to storage conditions. So, Cells should be stored in the situation of good airing in relative humidity $50\%\pm5\%$ and temperature $25^{\circ}C\pm5^{\circ}C$. Solar cells are extremely susceptible to the humidity. It is recommended to make panels using the cells within the Three months of the storage period for paramount performance.

Specifications subject to technical changes © Jupiter Solar Power Ltd